







CD74AC238

SCHS331A - FEBRUARY 2003 - REVISED APRIL 2024

CD74AC238 3-Line to 8-Line Decoder/Demultiplexer

1 Features

- AC types feature 1.5V to 5.5V operation and balanced noise immunity at 30% of the supply voltage
- Speed of bipolar F, AS, and S, with significantly reduced power consumption
- Designed specifically for high-speed memory decoders and data-transmission systems
- Incorporates three enable inputs to simplify cascading and/or data reception
- Balanced propagation delays
- ±24mA output drive current
 - Fanout to 15 F devices
- SCR-latchup-resistant CMOS process and circuit
- Exceeds 2kV ESD protection per MIL-STD-883, method 3015

2 Description

The CD74AC238 decoder/demultiplexer is designed for high-performance memory-decoding and dataapplications that require very propagation-delay times. In high-performance memory systems, this decoder can be used to minimize the effects of system decoding.

Package Information

PART NUMBER PACKAGE ⁽¹⁾		PACKAGE SIZE(2)	BODY SIZE(3)
CD74AC238	M (SOIC, 16)	9.9mm × 6mm	9.9mm × 3.9mm

- For more information, see Section 10.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.

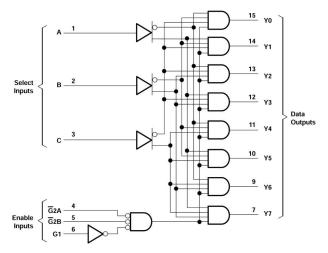




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3 Pin Configuration and Functions

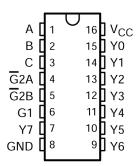


Figure 3-1. M Package (Top View)

Table 3-1. Pin Functions

PIN		TYPE(1)	DESCRIPTION				
NAME	NO.	- ITPE("/	DESCRIPTION				
А	1	I	Input A				
В	2	I	Input B				
С	3	I	out C				
G2A	4	I	Strobe Input 2A, active low				
G2B	5	I	Strobe Input 2B, active low				
G1	6	I	Strobe Input				
Y7	7	0	Output 7				
GND	8	G	Ground				
Y6	9	0	Output 6				
Y5	10	0	Output 5				
Y4	11	0	Output 4				
Y3	12	0	Output 3				
Y2	13	0	Output 2				
Y1	14	0	Output 1				
Y0	15	0	Output 0				
V _{CC}	16	Р	Positive Supply				
Thermal Pad ⁽²⁾		_	Thermal Pad				

⁽¹⁾ I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power.

⁽²⁾ BQB package only



4 Specifications

4.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	6	V
I _{IK} (2)	Input clamp current	$(V_I < 0 \text{ V or } V_I > V_{CC})$		±20	mA
I _{OK} (2)	Output clamp current	$(V_O < 0 \text{ V or } V_O > V_{CC})$		±50	mA
Io	Continuous output current	$(V_O > 0 \text{ V or } V_O < V_{CC})$		±50	mA
	Continuous current through V _{CC} or GND)		±200	mA
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

4.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

4.3 Recommended Operating Conditions

over recommended operating free-air temperature range (unless otherwise noted)(1)

			T _A = 25°C		-55°C to 12	5°C	-40°C to 8	5°C	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNII
V _{CC}	Supply voltage		1.5	5.5	1.5	5.5	1.5	5.5	V
		V _{CC} = 1.5 V	1.2		1.2		1.2		
V_{IH}	High-level input voltage	V _{CC} = 3 V	2.1		2.1		2.1		V
		V _{CC} = 5.5 V	3.85		3.85		3.85		
		V _{CC} = 1.5 V		0.3		0.3		0.3	
V _{IL}	Low-level input voltage	V _{CC} = 3 V		0.9		0.9		0.9	V
		V _{CC} = 5.5 v		1.65		1.65		1.65	
VI	Input voltage		0	V _{CC}	0	V _{CC}	0	V _{CC}	V
Vo	Output voltage		0	V _{CC}	0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 4.5 V to 5.5 V		-24		-24		-24	mA
I _{OL}	Low-level output current	V _{CC} = 4.5 V to 5.5 V		24		24		24	mA
		V _{CC} = 1.5 V to 3 V		50		50		50	
Δt/Δν	Input transition rise or fall rate	V _{CC} = 3.6 V to 5.5 V		20		20		20	ns/V

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

Product Folder Links: CD74AC238

²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



4.4 Thermal Information

		CD74AC238	
THERMAL METRIC(1)		M	UNIT
		16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	106.6	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

4.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	l v	$T_A = 28$	5 °C	-55°C to	125°C	-40°C to	85°C	UNIT
PARAWIETER	TEST COI	ADITIONS	V _{CC}	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
			1.5 V	1.4		1.4		1.4		
		I _{OH} = -50 μA	3 V	2.9		2.9		2.9		
			4.5 V	4.4		4.4		4.4		
V_{OH}	$V_I = V_{IH}$ or V_{IL}	I _{OH} = -4 mA	3 V	2.58		2.4		2.48		V
		I _{OH} = -24 mA	4.5 V	3.94		3.7		3.8		
		$I_{OH} = -50 \text{ mA}^{(1)}$	5.5 V			3.85				
		$I_{OH} = -75 \text{ mA}^{(1)}$	5.5 V					3.85		
			1.5 V		0.1		0.1		0.1	
		I _{OL} = 50 μA	3 V		0.1		0.1		0.1	
			4.5 V		0.1		0.1		0.1	
V_{OL}	$V_I = V_{IH}$ or V_{IL}	I _{OL} = 12 mA	3 V		0.36		0.5		0.44	V
		I _{OL} = 24 mA	4.5 V		0.36		0.5		0.44	
		I _{OL} = 50 mA ⁽¹⁾	5.5 V				1.65			
		I _{OL} = 75 mA ⁽¹⁾	5.5 V						1.65	
I ₁	V _I = V _{CC} or GND		5.5 V		±0.1		±1		±1	μA
I _{CC}	$V_I = V_{CC}$ or GND,	I _O = 0	5.5 V		8		160		80	μA
C _i					10		10		10	pF

⁽¹⁾ Test one output at a time, not exceeding 1-second duration. Measurement is made by forcing indicated current and measuring voltage to minimize power dissipation. Test verifies a minimum 50-Ω transmission-line drive capability at 85°C and 75-Ω transmission-line drive capability at 125°C.

4.6 Switching Characteristics, V_{CC} = 1.5 V

over recommended operating free-air temperature range, V_{CC} = 1.5 V, C_L = 50 pF (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	-55°C to 12	5°C	-40°C to	85°C	UNIT
PARAMETER	PROWI (INPUT)	10 (001701)	MIN	MAX	MIN	MAX	UNII
t _{PLH}	A P C	Any V		187		170	20
t _{PHL}	A, B, C	Any Y		187		170	ns
t _{PLH}	G1	Any Y		208		189	20
t _{PHL}	G I			208		189	ns
t _{PLH}	COA COB	Any V		149		135	20
t _{PHL}	G2A, G2B	Any Y		149		135	ns

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4.7 Switching Characteristics, $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V, C_L = 50 pF (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	DADAMETER FROM (INDUT) TO (OUT		-55°C to 1	125°C	-40°C to	UNIT	
PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	MIN	MAX	UNII
t _{PLH}	- A, B, C	Any V	5.3	21	5.4	19.1	no
t _{PHL}	А, Б, С	Any Y	5.3	21	5.4	19.1	ns
t _{PLH}	- G1	Any Y	5.8	23.2	6	21.1	ns
t _{PHL}	Gi		5.8	23.2	6	21.1	115
t _{PLH}	- <u>G</u> 2A, <u>G</u> 2B	Any V	4.2	16.7	4.3	15.2	no
t _{PHL}	GZA, GZB	Any Y	4.2	16.7	4.3	15.2	ns

4.8 Switching Characteristics, V_{CC} = 5 V ± 0.5 V

over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V, C_L = 50 pF (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	EDOM (INDLIT)	FROM (INPUT) TO (OUTPUT)		-55°C to 125°C		-40°C to 85°C	
PARAMETER	THOM (IIII 61)	10 (001701)	MIN	MAX	MIN	MAX	UNIT
t _{PLH}	A R C	Any V	3.8	15	3.9	13.6	ne
t _{PHL}	A, B, C	Any Y	3.8	15	3.9	13.6	ns
t _{PLH}	G1	Any Y	4.2	16.6	4.3	15.1	ns
t _{PHL}	Gi		4.2	16.6	4.3	15.1	115
t _{PLH}	G2A, G2B	Any V	3	11.9	3.1	10.7	no
t _{PHL}		Any Y	3	11.9	3.1	10.7	ns

4.9 Operating Characteristics

 V_{CC} = 5 V, T_A = 25°C

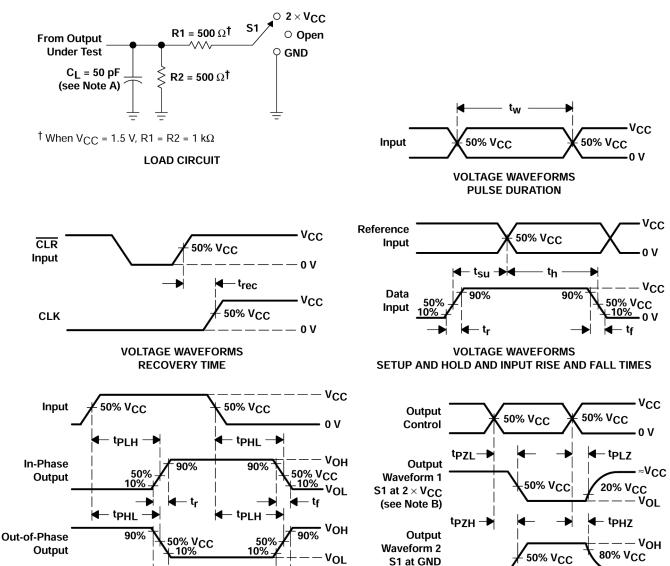
	PARAMETER	ТҮР	UNIT
(C _{pd} Power dissipation capacitance	110	

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5 Parameter Measurement Information



- C_L includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

(see Note B)

VOLTAGE WAVEFORMS

OUTPUT ENABLE AND DISABLE TIMES

- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 3$ ns, $t_f = 3$ ns. Phase relationships between waveforms are arbitrary.
- D. For clock inputs, f_{max} is measured with the input duty cycle at 50%.

VOLTAGE WAVEFORMS

PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

- E. The outputs are measured one at a time with one input transition per measurement.
- F. t_{PLH} and t_{PHL} are the same as t_{pd}.
- G. t_{PZL} and t_{PZH} are the same as t_{en} .
- H. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- I. All parameters and waveforms are not applicable to all devices.

Figure 5-1. Load Circuit and Voltage Waveforms



TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	2 × V _{CC}
t _{PHZ} /t _{PZH}	GND

6 Detailed Description

6.1 Overview

When employed with high-speed memories utilizing a fast enable circuit, the delay times of these decoders and the enable time of the memory usually are less than the typical access time of the memory. This means that the effective system delay introduced by the decoders is negligible.

The conditions at the binary-select inputs and the three enable inputs select one of eight output lines. Two active-low and one active-high enable inputs reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters, and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications (see Application Information).

6.2 Functional Block Diagram

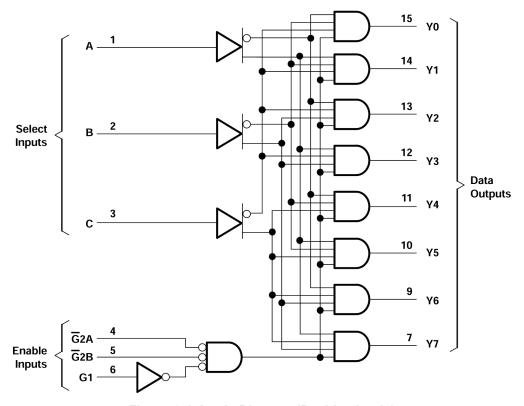


Figure 6-1. Logic Diagram (Positive Logic)

6.3 Device Functional Modes

Table 6-1. Function Table

	ENABLE IN	IPUTS	S	ELECT IN	NPUTS	OUTPUTS								
G1	G2A	G2B	С	В	Α	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7	
Х	Н	Х	Х	Х	Х	L	L	L	L	L	L	L	L	
Х	Х	Н	Х	Х	Х	L	L	L	L	L	L	L	L	
L	Х	Х	Х	Х	Х	L	L	L	L	L	L	L	L	
Н	L	L	L	L	L	Н	L	L	L	L	L	L	L	
Н	L	L	L	L	Н	L	Н	L	L	L	L	L	L	
Н	L	L	L	Н	L	L	L	Н	L	L	L	L	L	
Н	L	L	L	Н	Н	L	L	L	Н	L	L	L	L	
Н	L	L	Н	L	L	L	L	L	L	Н	L	L	L	
Н	L	L	Н	L	Н	L	L	L	L	L	Н	L	L	

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Table 6-1. Function Table (continued)

ENABLE INPUTS			S	ELECT IN	IPUTS	OUTPUTS							
G1	G2A	G2B	С	В	Α	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
Н	L	L	Н	Н	L	L	L	L	L	L	L	Н	L
Н	L	L	Н	Н	Н	L	L	L	L	L	L	L	Н



7 Application Information

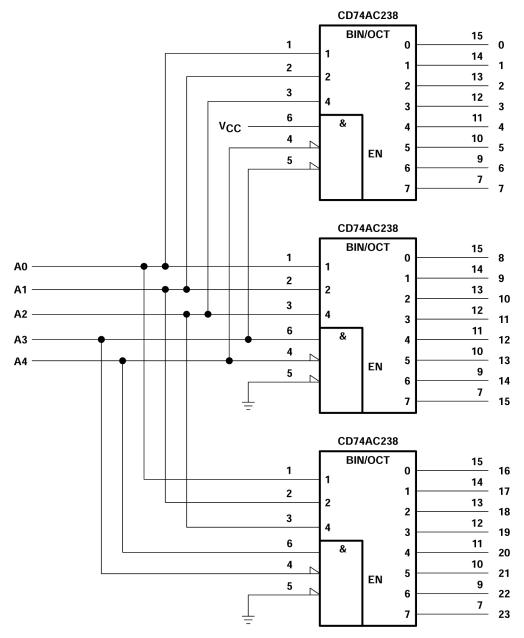


Figure 7-1. 24-Bit Decoding Scheme



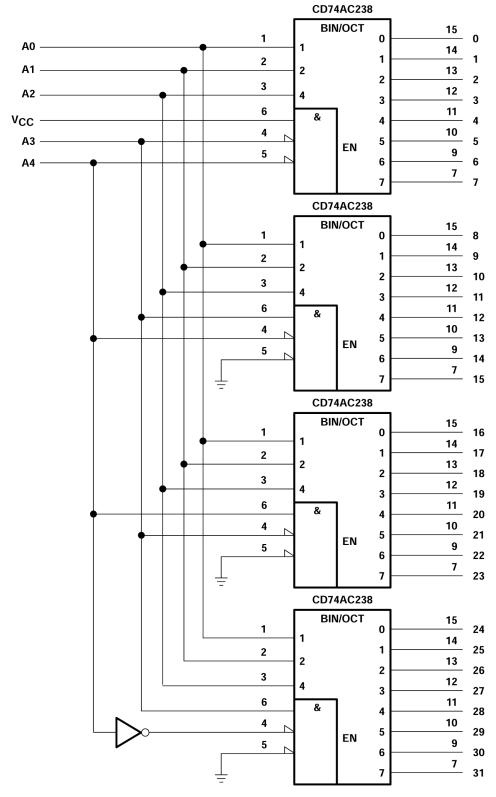


Figure 7-2. 32-Bit Decoding Scheme



7.1 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A $0.1\mu F$ capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The $0.1\mu F$ and $1\mu F$ capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

7.2 Layout

7.2.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

7.2.2 Layout Example

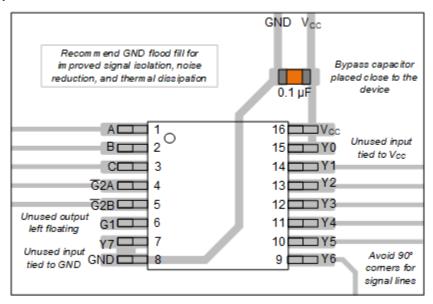


Figure 7-3. Example Layout for the CD74AC238



8 Device and Documentation Support

8.1 Documentation Support (Analog)

8.1.1 Related Documentation

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
CD74AC238	Click here	Click here	Click here	Click here	Click here

8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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8.4 Trademarks

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8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

Changes from Revision * (February 2003) to Revision A (April 2024)

Page

- Added Package Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device
 Functional Modes, Application and Implementation section, Device and Documentation Support section, and
 Mechanical, Packaging, and Orderable Information section

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
CD74AC238M96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC238M	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74AC238M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CD74AC238M96	SOIC	D	16	2500	340.5	336.1	32.0	

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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